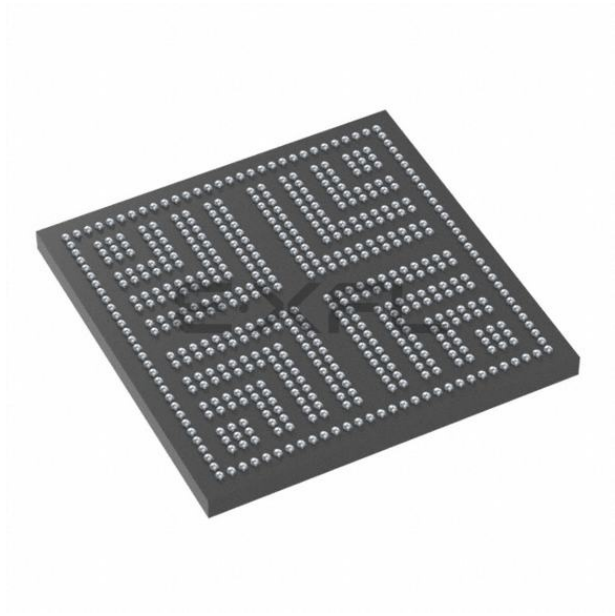

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Embedded - FPGAs, or Field Programmable Gate Arrays, are advanced integrated circuits that offer unparalleled flexibility and performance for digital systems. Unlike traditional fixed-function logic devices, FPGAs can be programmed and reprogrammed to execute a wide array of logical operations, enabling customized functionality tailored to specific applications. This reprogrammability allows developers to iterate designs quickly and implement complex functions without the need for custom hardware.

Applications of Embedded - FPGAs

The versatility of Embedded - FPGAs makes them indispensable in numerous fields. In telecommunications.

Details	
Product Status	Active
Number of LABs/CLBs	-
Number of Logic Elements/Cells	300000
Total RAM Bits	21094400
Number of I/O	300
Number of Gates	-
Voltage - Supply	0.97V ~ 1.08V
Mounting Type	Surface Mount
Operating Temperature	-40°C ~ 100°C (TJ)
Package / Case	536-LFBGA, CSPBGA
Supplier Device Package	536-CSPBGA (16x16)
Purchase URL	https://www.e-xfl.com/product-detail/microchip-technology/mpf300t-fcsg536i

4 Device Offering

The following table lists the PolarFire FPGA device options using the MPF300T as an example. The MPF100T, MPF200T, and MPF500T device densities have identical offerings.

Table 1 • PolarFire FPGA Device Options

Device Options	Extended Commercial 0 °C–100 °C	Industrial –40 °C–100 °C	STD	–1	Transceivers T	Lower Static Power L	Data Security S
MPF300T	Yes	Yes	Yes	Yes	Yes		
MPF300TL	Yes	Yes	Yes		Yes	Yes	
MPF300TS		Yes	Yes	Yes	Yes		Yes
MPF300TLS		Yes	Yes		Yes	Yes	Yes

5 Silicon Status

There are three silicon status levels:

- **Advanced**—initial estimated information based on simulations
- **Preliminary**—information based on simulation and/or initial characterization
- **Production**—final production silicon data

The following table shows the status of the PolarFire FPGA device.

Table 2 • PolarFire FPGA Silicon Status

Device	Silicon Status
MPF100T, TL, TS, TLS	Preliminary
MPF200T, TL, TS, TLS	Preliminary
MPF300T, TL, TS, TLS	Preliminary
MPF500T, TL, TS, TLS	Preliminary

6 DC Characteristics

This section lists the DC characteristics of the PolarFire FPGA device.

6.1 Absolute Maximum Rating

The following table lists the absolute maximum ratings for PolarFire devices.

Table 3 • Absolute Maximum Rating

Parameter	Symbol	Min	Max	Unit
FPGA core power supply	V_{DD}	–0.5	1.13	V
Transceiver Tx and Rx lanes supply	V_{DDA}	–0.5	1.13	V
Programming and HSIO receiver supply	V_{DD18}	–0.5	2.0	V
FPGA core and FPGA PLL high-voltage supply	V_{DD25}	–0.5	2.7	V
Transceiver PLL high-voltage supply	V_{DDA25}	–0.5	2.7	V
Transceiver reference clock supply	$V_{DD\_XCVR\_CLK}$	–0.5	3.6	V
Global V_{REF} for transceiver reference clocks	$XCVR_{VREF}$	–0.5	3.6	V
HSIO DC I/O supply[2]	V_{DDIx}	–0.5	2.0	V
GPIO DC I/O supply[2]	V_{DDIx}	–0.5	3.6	V
Dedicated I/O DC supply for JTAG and SPI	V_{DDI3}	–0.5	3.6	V
GPIO auxiliary power supply for I/O bank x[2]	V_{DDAUXx}	–0.5	3.6	V
Maximum DC input voltage on GPIO	V_{IN}	–0.5	3.8	V
Maximum DC input voltage on HSIO	V_{IN}	–0.5	2.2	V
Transceiver Receiver absolute input voltage	Transceiver V_{IN}	–0.5	1.26	V
Transceiver Reference clock absolute input voltage	Transceiver REFCLK V_{IN}	–0.5	3.6	V
Storage temperature (ambient)[1]	T_{STG}	–65	150	°C
Junction temperature[1]	T_J	–55	135	°C
Maximum soldering temperature RoHS	$T_{SOLROHS}$		260	°C
Maximum soldering temperature leaded	T_{SOLPB}		220	°C

1. See FPGA Programming Cycles vs Retention Characteristics for retention time vs. temperature. The total time used in calculating the device retention includes storage time and the device stored temperature.
2. The power supplies for a given I/O bank x are shown as VDDIx and VDDAUXx.

6.2 Recommended Operating Conditions

The following table lists the recommended operating conditions.

Table 4 • Recommended Operating Conditions

Parameter	Symbol	Min	Typ	Max	Unit
FPGA core supply at 1.0 V mode[1]	V_{DD}	0.97	1.00	1.03	V
FPGA core supply at 1.05 V mode[1]	V_{DD}	1.02	1.05	1.08	V
Transceiver TX and RX lanes supply at 1.0 V mode (when all lane rates are 10.3125 Gbps or less)[1]	V_{DDA}	0.97	1.00	1.03	V

I/O Standard	V_{DDI} Min (V)	V_{DDI} Typ (V)	V_{DDI} Max (V)	V_{IL} Min (V)	V_{IL} Max (V)	V_{IH} Min (V)	V_{IH}[1] Max (V)
SSTL135I	1.283	1.35	1.418	–0.3	V_{REF} – 0.09	V_{REF} + 0.09	1.418
SSTL135II	1.283	1.35	1.418	–0.3	V_{REF} – 0.09	V_{REF} + 0.09	1.418
HSTL15I	1.425	1.5	1.575	–0.3	V_{REF} – 0.1	V_{REF} + 0.1	1.575
HSTL15II	1.425	1.5	1.575	–0.3	V_{REF} – 0.1	V_{REF} + 0.1	1.575
HSTL135I	1.283	1.35	1.418	–0.3	V_{REF} – 0.09	V_{REF} + 0.09	1.418
HSTL135II	1.283	1.35	1.418	–0.3	V_{REF} – 0.09	V_{REF} + 0.09	1.418
HSTL12I	1.14	1.2	1.26	–0.3	V_{REF} – 0.1	V_{REF} + 0.1	1.26
HSTL12II	1.14	1.2	1.26	–0.3	V_{REF} – 0.1	V_{REF} + 0.1	1.26
HSUL18I	1.71	1.8	1.89	–0.3	0.3 × V_{DDI}	0.7 × V_{DDI}	1.89
HSUL18II	1.71	1.8	1.89	–0.3	0.3 × V_{DDI}	0.7 × V_{DDI}	1.89
HSUL12I	1.14	1.2	1.26	–0.3	V_{REF} – 0.1	V_{REF} + 0.1	1.26
POD12I	1.14	1.2	1.26	–0.3	V_{REF} – 0.08	V_{REF} + 0.08	1.26
POD12II	1.14	1.2	1.26	–0.3	V_{REF} – 0.08	V_{REF} + 0.08	1.26

1. GPIO V_{IH} max is 3.45 V with PCI clamp diode turned off regardless of mode, that is, over-voltage tolerant.
2. For external stub-series resistance. This resistance is on-die for GPIO.

Note: 3.3 V and 2.5 V are only supported in GPIO banks.

Table 13 • DC Output Levels

I/O Standard	V_{DDI} Min (V)	V_{DDI} Typ (V)	V_{DDI} Max (V)	V_{OL} Min (V)	V_{OL} Max (V)	V_{OH} Min (V)	V_{OH} Max (V)	I_{OL}[2,6] mA	I_{OH}[2,6] mA
PCI[1]	3.15	3.3	3.45		0.1 × V_{DDI}	0.9 × V_{DDI}		1.5	0.5
LVTTL	3.15	3.3	3.45		0.4	2.4			
LVCMOS33	3.15	3.3	3.45		0.4	V_{DDI} – 0.4			
LVCMOS25	2.375	2.5	2.625		0.4	V_{DDI} – 0.4			
LVCMOS18	1.71	1.8	1.89		0.45	V_{DDI} – 0.45			
LVCMOS15	1.425	1.5	1.575		0.25 × V_{DDI}	0.75 × V_{DDI}			
LVCMOS12	1.14	1.2	1.26		0.25 × V_{DDI}	0.75 × V_{DDI}			
SSTL25I[3]	2.375	2.5	2.625		V_{TT} – 0.608	V_{TT} + 0.608		8.1	8.1
SSTL25II[3]	2.375	2.5	2.625		V_{TT} – 0.810	V_{TT} + 0.810		16.2	16.2
SSTL18I[3]	1.71	1.8	1.89		V_{TT} – 0.603	V_{TT} + 0.603		6.7	6.7
SSTL18II[3]	1.71	1.8	1.89		V_{TT} – 0.603	V_{TT} + 0.603		13.4	13.4
SSTL15I[4]	1.425	1.5	1.575		0.2 × V_{DDI}	0.8 × V_{DDI}		V_{OL}/40	(V_{DDI} – V_{OH}) /40
SSTL15II[4]	1.425	1.5	1.575		0.2 × V_{DDI}	0.8 × V_{DDI}		V_{OL}/34	(V_{DDI} – V_{OH}) /34
SSTL135I[4]	1.283	1.35	1.418		0.2 × V_{DDI}	0.8 × V_{DDI}		V_{OL}/40	(V_{DDI} – V_{OH}) /40
SSTL135II[4]	1.283	1.35	1.418		0.2 × V_{DDI}	0.8 × V_{DDI}		V_{OL}/34	(V_{DDI} – V_{OH}) /34
HSTL15I	1.425	1.5	1.575		0.4	V_{DDI} – 0.4		8	8
HSTL15II	1.425	1.5	1.575		0.4	V_{DDI} – 0.4		16	16

I/O Standard	Bank Type	VICM_RANGE Libero Setting	V_{ICM}[1,3] Min (V)	V_{ICM}[1,3] Typ (V)	V_{ICM}[1,3] Max (V)	V_{ID}[2] Min (V)	V_{ID} Typ (V)	V_{ID} Max (V)
HCSL25[6]	GPIO	Mid (default)	0.6	1.25	2.35	0.1	0.55	1.1
		Low	0.05	0.35	0.8	0.1	0.55	1.1
HCSL18[5]	HSIO	Mid (default)	0.6	1.0	1.65	0.1	0.55	1.1
		Low	0.05	0.4	0.8	0.1	0.55	1.1
BUSLVDSE25	GPIO	Mid (default)	0.6	1.25	2.35	0.05	0.1	V_{DDIn}
		Low	0.05	0.4	0.8	0.05	0.1	V_{DDIn}
MLVDSE25	GPIO	Mid (default)	0.6	1.25	2.35	0.05	0.35	2.4
		Low	0.05	0.4	0.8	0.05	0.35	2.4
LVPECL33	GPIO	Mid (default)	0.6	1.65	2.35	0.05	0.8	2.4
		Low	0.05	0.4	0.8	0.05	0.8	2.4
LVPECLE33	GPIO	Mid (default)	0.6	1.65	2.35	0.05	0.8	2.4
		Low	0.05	0.4	0.8	0.05	0.8	2.4
MIPI25	GPIO	Mid (default)	0.6	1.25	2.35	0.05	0.2	0.3
		Low	0.05	0.2	0.8	0.05	0.2	0.3

1. V_{ICM} is the input common mode.
2. V_{ID} is the input differential voltage.
3. V_{ICM} rules are as follows:
   a. V_{ICM} must be less than V_{DDI} – 0.4 V;
   b. V_{ICM} + V_{ID}/2 must be <V_{DDI} + 0.4 V;
   c. V_{ICM} – V_{ID}/2 must be >VSS – 0.3 V;
   d. Any differential input with V_{ICM} ≤0.6 V requires the low common mode setting in Libero (VICM_RANGE=LOW).
4. VDDI = 1.8 V, VDDAUX = 2.5 V.
5. HSIO receiver only.
6. GPIO receiver only.

Table 15 • Differential DC Output Levels

I/O Standard	Bank Type	V_{OCM}[1] Min (V)	V_{OCM} Typ (V)	V_{OCM} Max (V)	V_{OD}[2] Min (V)	V_{OD}[2] Typ (V)	V_{OD}[2] Max (V)
LVDS33	GPIO		1.2		0.25	0.35	0.45
LVDS25	GPIO		1.2		0.25	0.35	0.45
LCMDS33	GPIO		0.6		0.25	0.35	0.45
LCMDS25	GPIO		0.6		0.25	0.35	0.45
RSDS33	GPIO		1.2		0.17	0.2	0.23
RSDS25	GPIO		1.2		0.17	0.2	0.23
MINILVDS33	GPIO		1.2		0.3	0.4	0.6
MINILVDS25	GPIO		1.2		0.3	0.4	0.6
SUBLVDS33	GPIO		0.9		0.1	0.15	0.3
SUBLVDS25	GPIO		0.9		0.1	0.15	0.3
PPDS33	GPIO		0.8		0.17	0.2	0.23
PPDS25	GPIO		0.8		0.17	0.2	0.23
SLVSE15[3]	GPIO, HSIO		0.2		0.12	0.135	0.15
BUSLVDSE25[3]	GPIO		1.25		0.24	0.262	0.272

7 AC Switching Characteristics

This section contains the AC switching characteristics of the PolarFire FPGA device.

7.1 I/O Standards Specifications

This section describes I/O delay measurement methodology, buffer speed, switching characteristics, digital latency, gearing training calibration, and maximum physical interface (PHY) rate for memory interface IP.

7.1.1 Input Delay Measurement Methodology Maximum PHY Rate for Memory Interface IP

The following table provides information about the methodology for input delay measurement.

Table 22 • Input Delay Measurement Methodology

Standard	Description	V_L[1]	V_H[1]	V_{ID}[2]	V_{ICM}[2]	V_{MEAS}[3, 4]	V_{REF}[1, 5]	Unit
PCI	PCIE 3.3 V	0	VDDI			VDDI/2		V
LVTTL33	LVTTL 3.3 V	0	VDDI			VDDI/2		V
LVCMOS33	LVCMOS 3.3 V	0	VDDI			VDDI/2		V
LVCMOS25	LVCMOS 2.5 V	0	VDDI			VDDI/2		V
LVCMOS18	LVCMOS 1.8 V	0	VDDI			VDDI/2		V
LVCMOS15	LVCMOS 1.5 V	0	VDDI			VDDI/2		V
LVCMOS12	LVCMOS 1.2 V	0	VDDI			VDDI/2		V
SSTL25I	SSTL 2.5 V Class I	V_{REF} – 0.5	V_{REF} + 0.5			V_{REF}	1.25	V
SSTL25II	SSTL 2.5 V Class II	V_{REF} – 0.5	V_{REF} + 0.5			V_{REF}	1.25	V
SSTL18I	SSTL 1.8 V Class I	V_{REF} – 0.5	V_{REF} + 0.5			V_{REF}	0.90	V
SSTL18II	SSTL 1.8 V Class II	V_{REF} – 0.5	V_{REF} + 0.5			V_{REF}	0.90	V
SSTL15I	SSTL 1.5 V Class I	V_{REF} – .175	V_{REF} + .175			V_{REF}	0.75	V
SSTL15II	SSTL 1.5 V Class II	V_{REF} – .175	V_{REF} + .175			V_{REF}	0.75	V
SSTL135I	SSTL 1.35 V Class I	V_{REF} – .16	V_{REF} + .16			V_{REF}	0.675	V
SSTL135II	SSTL 1.35 V Class II	V_{REF} – .16	V_{REF} + .16			V_{REF}	0.675	V
HSTL15I	HSTL 1.5 V Class I	V_{REF} – .5	V_{REF} + .5			V_{REF}	0.75	V
HSTL15II	HSTL 1.5 V Class II	V_{REF} – .5	V_{REF} + .5			V_{REF}	0.75	V
HSTL135I	HSTL 1.35 V Class I	V_{REF} – 0.45	V_{REF} + . 45			V_{REF}	0.675	V
HSTL135II	HSTL 1.35 V Class II	V_{REF} – .45	V_{REF} + .45			V_{REF}	0.675	V
HSTL12	HSTL 1.2 V	V_{REF} – .4	V_{REF} + .4			V_{REF}	0.60	V

Standard	Description	V_L[1]	V_H[1]	V_{ID}[2]	V_{ICM}[2]	V_{MEAS}[3,4]	V_{REF}[1,5]	Unit
HSTL135II	Differential HSTL 1.35 V Class II	V_{ICM} – .125	V_{ICM} + .125	0.250	0.675	0		V
HSTL12	Differential HSTL 1.2 V	V_{ICM} – .125	V_{ICM} + .125	0.250	0.600	0		V
HSUL18I	Differential HSUL 1.8 V Class I	V_{ICM} – .125	V_{ICM} + .125	0.250	0.900	0		V
HSUL18II	Differential HSUL 1.8 V Class II	V_{ICM} – .125	V_{ICM} + .125	0.250	0.900	0		V
HSUL12	Differential HSUL 1.2 V	V_{ICM} – .125	V_{ICM} + .125	0.250	0.600	0		V
POD12I	Differential POD 1.2 V Class I	V_{ICM} – .125	V_{ICM} + .125	0.250	0.600	0		V
POD12II	Differential POD 1.2 V Class II	V_{ICM} – .125	V_{ICM} + .125	0.250	0.600	0		V
MIPI25	Mobile Industry Processor Interface	V_{ICM} – .125	V_{ICM} + .125	0.250	0.200	0		V

1. Measurements are made at typical, minimum, and maximum V_{REF} values. Reported delays reflect worst-case of these measurements. V_{REF} values listed are typical. Input waveform switches between V_L and V_H. All rise and fall times must be 1 V/ns.
2. Differential receiver standards all use 250 mV V_{ID} for timing. V_{CM} is different between different standards.
3. Input voltage level from which measurement starts.
4. The value given is the differential input voltage.
5. This is an input voltage reference that bears no relation to the V_{REF}/V_{MEAS} parameters found in IBIS models or shown in Output Delay Measurement—Single-Ended Test Setup (see page 27).
6. Emulated bi-directional interface.

7.1.2 Output Delay Measurement Methodology

The following section provides information about the methodology for output delay measurement.

Table 23 • Output Delay Measurement Methodology

Standard	Description	R_{REF} (Ω)	C_{REF} (pF)	V_{MEAS} (V)	V_{REF} (V)
PCI	PCIE 3.3 V	25	10	1.65	
LVTTL33	LVTTL 3.3 V	1M	0	1.65	
LVCMOS33	LVCMOS 3.3 V	1M	0	1.65	
LVCMOS25	LVCMOS 2.5 V	1M	0	1.25	
LVCMOS18	LVCMOS 1.8 V	1M	0	0.90	
LVCMOS15	LVCMOS 1.5 V	1M	0	0.75	
LVCMOS12	LVCMOS 1.2 V	1M	0	0.60	
SSTL25I	Stub-series terminated logic 2.5 V Class I	50	0	V_{REF}	1.25
SSTL25II	SSTL 2.5 V Class II	50	0	V_{REF}	1.25

Figure 1 • Output Delay Measurement—Single-Ended Test Setup

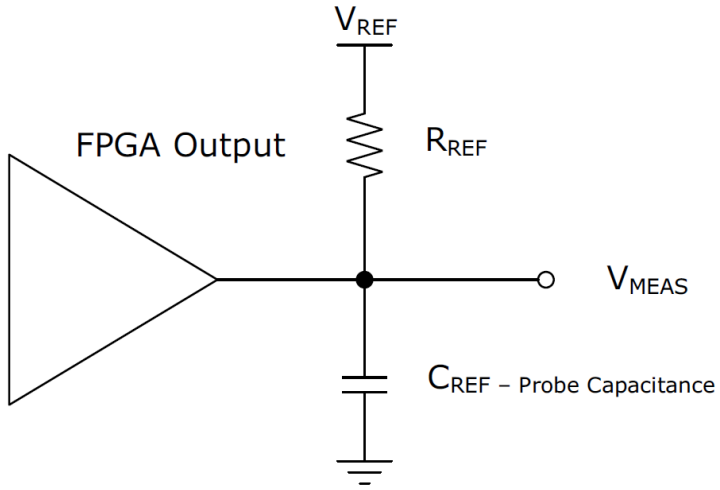
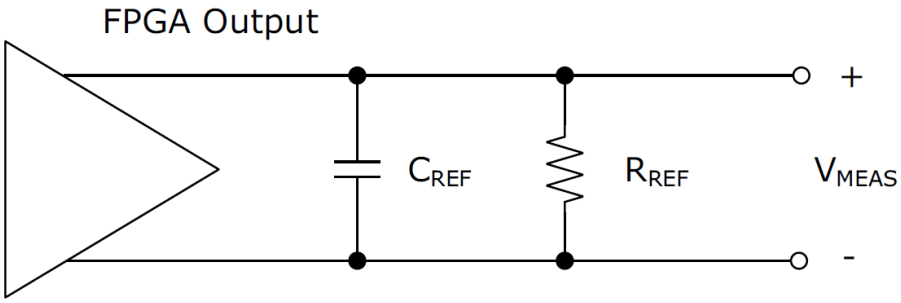


Figure 2 • Output Delay Measurement—Differential Test Setup



7.1.3 Input Buffer Speed

The following tables provide information about input buffer speed.

Table 24 • HSIO Maximum Input Buffer Speed

Standard	STD	–1	Unit
LVDS18	1250	1250	Mbps
RSDS18	800	800	Mbps
MINILVDS18	800	800	Mbps
SUBLVDS18	800	800	Mbps
PPDS18	800	800	Mbps
SLVS18	800	800	Mbps
SSTL18I	800	1066	Mbps
SSTL18II	800	1066	Mbps
SSTL15I	1066	1333	Mbps
SSTL15II	1066	1333	Mbps
SSTL135I	1066	1333	Mbps
SSTL135II	1066	1333	Mbps

Standard	STD	–1	Unit
LVCMOS18 (12 mA)	500	500	Mbps
LVCMOS15 (10 mA)	500	500	Mbps
LVCMOS12 (8 mA)	300	300	Mbps
MIPI25/MIPI33	800	800	Mbps

1. All SSTLD/HSTLD/HSULD/LVSTLD/POD type receivers use the LVDS differential receiver.
2. Performance is achieved with V_{ID} ≥200 mV.

7.1.4 Output Buffer Speed

Table 26 • HSIO Maximum Output Buffer Speed

Standard	STD	–1	Unit
SSTL18I	800	1066	Mbps
SSTL18II	800	1066	Mbps
SSTL18I (differential)	800	1066	Mbps
SSTL18II (differential)	800	1066	Mbps
SSTL15I	1066	1333	Mbps
SSTL15II	1066	1333	Mbps
SSTL15I (differential)	1066	1333	Mbps
SSTL15II (differential)	1066	1333	Mbps
SSTL135I	1066	1333	Mbps
SSTL135II	1066	1333	Mbps
SSTL135I (differential)	1066	1333	Mbps
SSTL135II (differential)	1066	1333	Mbps
HSTL15I	900	1100	Mbps
HSTL15II	900	1100	Mbps
HSTL15I (differential)	900	1100	Mbps
HSTL15II (differential)	900	1100	Mbps
HSTL135I	1066	1066	Mbps
HSTL135II	1066	1066	Mbps
HSTL135I (differential)	1066	1066	Mbps
HSTL135II (differential)	1066	1066	Mbps
HSUL18I	400	400	Mbps
HSUL18II	400	400	Mbps
HSUL18II (differential)	400	400	Mbps
HSUL12	1066	1333	Mbps
HSUL12I (differential)	1066	1333	Mbps
HSTL12	1066	1266	Mbps
HSTL12I (differential)	1066	1266	Mbps
POD12I	1333	1600	Mbps
POD12II	1333	1600	Mbps
LVCMOS18 (12 mA)	500	500	Mbps
LVCMOS15 (10 mA)	500	500	Mbps

Parameter	Interface Name	Topology	STD Min	STD Typ	STD Max	–1 Min	–1 Typ	–1 Max	Unit	Forwarded Clock-to-Data Skew
Output F_{MAX} 2:1	TX_DDRX_B_C	Tx DDR digital mode							MHz	From a HS_IO_CLK clock source, centered with PLL
Output F_{MAX} 4:1	TX_DDRX_B_C	Tx DDR digital mode							MHz	From a HS_IO_CLK clock source, centered with PLL
Output F_{MAX} 8:1	TX_DDRX_B_C	Tx DDR digital mode							MHz	From a HS_IO_CLK clock source, centered with PLL
In delay, out delay, DLL delay step sizes			12.7	30	35	12.7	25	29.5	ps	

Table 34 • I/O CDR Switching Characteristics

Parameter	Min	Max	Unit
Data rate	266	1250	Mbps
Receiver Sinusoidal jitter tolerance[1]	0.2		UI

1. Jitter values based on bit error ratio (BER) of 10–12, 80 MHz sinusoidal jitter injected to Rx data.

Note: See the LVDS output buffer specifications for transmit characteristics.

7.2 Clocking Specifications

This section describes the PLL and DLL clocking and oscillator specifications.

7.2.1 Clocking

The following table provides clocking specifications.

Table 35 • Global and Regional Clock Characteristics (–40 °C to 100 °C)

Parameter	Symbol	V_{DD} = 1.0 V STD	V_{DD} = 1.0 V –1	V_{DD} = 1.05 V STD	V_{DD} = 1.05 V –1	Unit	Condition
Global clock F_{MAX}	F_{MAXG}	500	500	500	500	MHz	
Regional clock F_{MAX}	F_{MAXR}	375	375	375	375	MHz	Transceiver interfaces only
	F_{MAXR}	250	250	250	250	MHz	All other interfaces
Global clock duty cycle distortion	T_{DCDG}	190	190	190	190	ps	At 500 MHz

Parameter	Symbol	V_{DD} = 1.0 V STD	V_{DD} = 1.0 V –1	V_{DD} = 1.05 V STD	V_{DD} = 1.05 V –1	Unit	Condition
Regional clock duty cycle distortion	T_{DCDR}	120	120	120	120	ps	At 250 MHz

The following table provides clocking specifications from –40 °C to 100 °C.

Table 36 • High-Speed I/O Clock Characteristics (–40 °C to 100 °C)

Parameter	Symbol	V_{DD} = 1.0 V STD	V_{DD} = 1.0 V –1	V_{DD} = 1.05 V STD	V_{DD} = 1.05 V –1	Unit	Condition
High-speed I/O clock F_{MAX}	F_{MAXB}	1000	1250	1000	1250	MHz	HSIO and GPIO
High-speed I/O clock skew[1]	F_{SKEWB}	30	20	30	20	ps	HSIO without bridging
	F_{SKEWB}	600	500	600	500	ps	HSIO with bridging
	F_{SKEWB}	45	35	45	35	ps	GPIO without bridging
	F_{SKEWB}	75	60	75	60	ps	GPIO with bridging
High-speed I/O clock duty cycle distortion[2]	T_{DCB}	90	90	90	90	ps	HSIO without bridging
	T_{DCB}	115	115	115	115	ps	HSIO with bridging
	T_{DCB}	90	90	90	90	ps	GPIO without bridging
	T_{DCB}	115	115	115	115	ps	GPIO with bridging

1. F_{SKEWB} is the worst-case clock-tree skew observable between sequential I/O elements. Clock-tree skew is significantly smaller at I/O registers close to each other and fed by the same or adjacent clock-tree branches. Use the Microsemi Timing Analyzer tool to evaluate clock skew specific to the design.
2. Parameters listed in this table correspond to the worst-case duty cycle distortion observable at the I/O flip flops. IBIS should be used to calculate any additional duty cycle distortion that might be caused by asymmetrical rise/fall times for any I/O standard.

7.2.2 PLL

The following table provides information about PLL.

Table 37 • PLL Electrical Characteristics

Parameter	Symbol	Min	Typ	Max	Unit
Input clock frequency (integer mode)	F_{INI}	1		1250	MHz
Input clock frequency (fractional mode)	F_{INF}	10		1250	MHz
Minimum reference or feedback pulse width[1]	$F_{INPULSE}$	200			ps
Frequency at the Frequency Phase Detector (PFD) (integer mode)	F_{PHDETI}	1		312	MHz
Frequency at the PFD (fractional mode)	F_{PHDETF}	10	50	125	MHz
Allowable input duty cycle	F_{INDUTY}	25		75	%

Parameter	Symbol	Min	Typ	Max	Unit
Maximum input period clock jitter (reference and feedback clocks)[2]	F_{MAXINJ}		120	1000	ps
PLL VCO frequency	F_{VCO}	800		5000	MHz
Loop bandwidth (Int)[3]	F_{BW}	F_{PHDET}/55	F_{PHDET}/44	F_{PHDET}/30	MHz
Loop bandwidth (FRAC)[3]	F_{BW}	F_{PHDET}/91	F_{PHDET}/77	F_{PHDET}/56	MHz
Static phase offset of the PLL outputs[4]	T_{SPO}			Max (±60 ps, ±0.5 degrees)	ps
	$T_{OUTJITTER}$				ps
PLL output duty cycle precision	$T_{OUTDUTY}$	48		54	%
PLL lock time[5]	T_{LOCK}			Max (6.0 µs, 625 PFD cycles)	µs
PLL unlock time[6]	T_{UNLOCK}	2		8	PFD cycles
PLL output frequency	F_{OUT}	0.050		1250	MHz
Minimum reset pulse width	T_{MRPW}				µs
Maximum delay in the feedback path[7]	F_{MAXDFB}			1.5	PFD cycles
Spread spectrum modulation spread[8]	Mod_Spread	0.1		3.1	%
Spread spectrum modulation frequency[9]	Mod_Freq	F_{PHDETF}/(128x63)	32	F_{PHDETF}/(128)	KHz

1. Minimum time for high or low pulse width.
2. Maximum jitter the PLL can tolerate without losing lock.
3. Default bandwidth setting of BW_PROP_CTRL = "01" for Integer and Fraction modes leads to the typical estimated bandwidth. This bandwidth can be lowered by setting BW_PROP_CTRL = "00" and can be increased if BW_PROP_CTRL = "10" and will be at the highest value if BW_PROP_CTRL = "11".
4. Maximum (±3-Sigma) phase error between any two outputs with nominally aligned phases.
5. Input clock cycle is REFDIV/F_{REF}. For example, F_{REF} = 25 MHz, REFDIV = 1, lock time = 10.0 (assumes LOCKCOUNTSEL setting = 4'd8 (256 cycles)).
6. Unlock occurs if two cycle slip within LOCKCOUNT/4 PFD cycles.
7. Maximum propagation delay of external feedback path in deskew mode.
8. Programmable capability for depth of down spread or center spread modulation.
9. Programmable modulation rate based on the modulation divider setting (1 to 63).

Note: In order to meet all data sheet specifications, the PLL must be programmed such that the PLL Loop Bandwidth < (0.0017 * VCO Frequency) – 0.4863 MHz. The Libero PLL configuration tool will enforce this rule when creating PLL configurations.

7.2.3 DLL

The following table provides information about DLL.

Table 38 • DLL Electrical Characteristics

Parameter[1]	Symbol	Min	Typ	Max	Unit
Input reference clock frequency	F_{INF}	133		800	MHz
Input feedback clock frequency	F_{INFDBF}	133		800	MHz
Primary output clock frequency	F_{OUTPF}	133		800	MHz

7.3.2 SRAM Blocks

The following tables describe the LSRAM blocks' performance.

Table 43 • LSRAM Performance Industrial Temperature Range (–40 °C to 100 °C)

Parameter	V_{DD} = 1.0 V – STD	V_{DD} = 1.0 V – 1	V_{DD} = 1.05 V – STD	V_{DD} = 1.05 V – 1	Unit	Condition
Operating frequency	343	428	343	428	MHz	Two-port, all supported widths, pipelined, simple-write, and write-feed-through
	309	428	309	428	MHz	Two-port, all supported widths, non-pipelined, simple-write, and write-feed-through
	343	428	343	428	MHz	Dual-port, all supported widths, pipelined, simple-write, and write-feed-through
	309	428	309	428	MHz	Dual-port, all supported widths, non-pipelined, simple-write, and write-feed-through
	343	428	343	428	MHz	Two-port pipelined ECC mode, pipelined, simple-write, and write-feed-through
	279	295	279	295	MHz	Two-port non-pipelined ECC mode, pipelined, simple-write, and write-feed-through
	343	428	343	428	MHz	Two-port pipelined ECC mode, non-pipelined, simple-write, and write-feed-through
	196	285	196	285	MHz	Two-port non-pipelined ECC mode, non-pipelined, simple-write, and write-feed-through
	274	285	274	285	MHz	Two-port, all supported widths, pipelined, and read-before-write
	274	285	274	285	MHz	Two-port, all supported widths, non-pipelined, and read-before-write
	274	285	274	285	MHz	Dual-port, all supported widths, pipelined, and read-before-write
	274	285	274	285	MHz	Dual-port, all supported widths, non-pipelined, and read-before-write
	274	285	274	285	MHz	Two-port pipelined ECC mode, pipelined, and read-before-write
	274	285	274	285	MHz	Two-port non-pipelined ECC mode, pipelined, and read-before-write
	274	285	274	285	MHz	Two-port pipelined ECC mode, non-pipelined, and read-before-write
	193	285	193	285	MHz	Two-port non-pipelined ECC mode, non-pipelined, and read-before-write

Parameter	Symbol	STD Min	STD Typ	STD Max	–1 Min	–1 Typ	–1 Max	Unit
Reference clock input rate[1, 2, 3]	$F_{XCVRREFCLKMAX\ CASCADE}$	20		156	20		156	MHz
Reference clock rate at the PFD[4]	$F_{TXREFCLKPFD}$	20		156	20		156	MHz
Reference clock rate recommended at the PFD for Tx rates 10 Gbps and above[4]	$F_{TXREFCLKPFD10G}$	75		156	75		156	MHz
Tx reference clock phase noise requirements to meet jitter specifications (156 MHz clock at reference clock input)[5]	$F_{TXREFPN}$			–110			–110	dBc /Hz
Phase noise at 10 KHz	$F_{TXREFPN}$			–110			–110	dBc /Hz
Phase noise at 100 KHz	$F_{TXREFPN}$			–115			–115	dBc /Hz
Phase noise at 1 MHz	$F_{TXREFPN}$			–135			–135	dBc /Hz
Reference clock input rise time (10%–90%)	$T_{REFRISE}$		200	500		200	500	ps
Reference clock input fall time (90%–10%)	$T_{REFFALL}$		200	500		200	500	ps
Reference clock duty cycle	$T_{REFDUTY}$	40		60	40		60	%
Spread spectrum modulation spread[6]	Mod_Spread	0.1		3.1	0.1		3.1	%
Spread spectrum modulation frequency[7]	Mod_Freq	TxREF CLKPFD/ (128)	32	TxREF CLKPFD/ (128*63)	TxREF CLKPFD/ (128)	32	TxREF CLKPFD/ (128*63)	KHz

1. See the maximum reference clock rate allowed per input buffer standard.
2. The minimum value applies to this clock when used as an XCVR reference clock. It does not apply when used as a non-XCVR input buffer (DC input allowed).
3. Cascaded reference clock.
4. After reference clock input divider.
5. Required maximum phase noise is scaled based on actual $F_{TxRefClkPFD}$ value by 20 × log10 (TxRefClkPFD /156 MHz). It is assumed that the reference clock divider of 4 is used for these calculations to always meet the maximum PFD frequency specification.
6. Programmable capability for depth of down-spread or center-spread modulation.
7. Programmable modulation rate based on the modulation divider setting (1 to 63).

7.4.3 Transceiver Reference Clock I/O Standards

The following table describes the differential I/O standards supported as transceiver reference clocks.

Parameter	Typ	Max	Unit	Conditions
Time to destroy data in non-volatile memory (non-recoverable)[1, 4]			ms	One iteration of scrubbing
Time to scrub the fabric data[1]			s	Full scrubbing
Time to scrub the pNVM data (like new)[1, 2]			s	Full scrubbing
Time to scrub the pNVM data (recoverable)[1, 3]			s	Full scrubbing
Time to scrub the fabric data pNVM data (non-recoverable)[1]			s	Full scrubbing
Time to verify[5]			s	

1. Total completion time after entering zeroization.
2. Like new mode—zeroizes user design security setting and sNVM content.
3. Recoverable mode—zeroizes user design security setting, sNVM and factory keys.
4. Non-recoverable mode—zeroizes user design security setting, sNVM and factory keys, and factory data required for programming.
5. Time to verify after scrubbing completes.

7.6.7 Verify Time

The following tables describe verify time.

Table 81 • Standalone Fabric Verify Times

Parameter	Devices	Max	Unit
Standalone verification over JTAG	MPF100T, TL, TS, TLS		s
	MPF200T, TL, TS, TLS	53[1]	s
	MPF300T, TL, TS, TLS	90[1]	s
	MPF500T, TL, TS, TLS		s
Standalone verification over SPI	MPF100T, TL, TS, TLS		s
	MPF200T, TL, TS, TLS	37[2]	s
	MPF300T, TL, TS, TLS	55[2]	s
	MPF500T, TL, TS, TLS		s

1. Programmer: FlashPro5, TCK 10 MHz; PC configuration: Intel i7 at 3.6 GHz, 32 GB RAM, Windows 10.
2. SmartFusion2 with MSS running at 100 MHz, MSS_SPI_0 port running at 6.67 MHz. DirectC version 4.1.

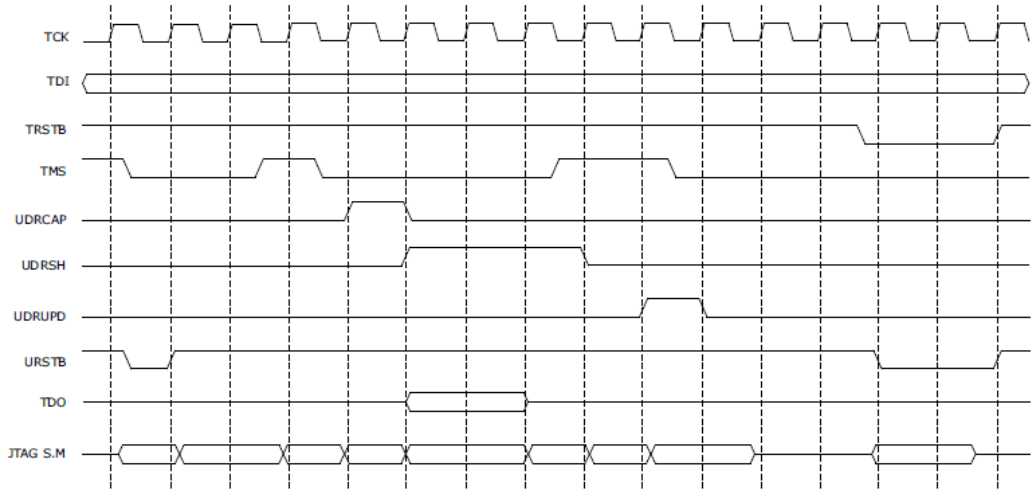
Notes:

- Standalone verify is limited to 2,000 total device hours ove r the industrial –40 °C to 100 °C temperature.
- Use the digest system service, for verify device time more than 2,000 hours.
- Standalone verify checks the programming margin on both the P and N gates of the push-pull cell.
- Digest checks only the P side of the push-pull gate. However, the push-pull gates work in tandem. Digest check is recommended if users believe they will exceed the 2,000-hour verify time specification.

Table 82 • Verify Time by Programming Hardware

Devices	IAP	FlashPro4	FlashPro5	BP	Silicon Sculptor	Units
MPF100T, TL, TS, TLS						
MPF200T, TL, TS, TLS	9	67	53			s
MPF300T, TL, TS, TLS	14	95	90			s

Figure 3 • UJTAG Timing Diagram



7.8.2 UJTAG_SEC Switching Characteristics

The following table describes characteristics of UJTAG_SEC switching.

Table 89 • UJTAG Security Performance Characteristics

Parameter	Symbol	Min	Typ	Max	Unit	Condition
TCK frequency	F_{TCK}				MHz	

7.8.3 USPI Switching Characteristics

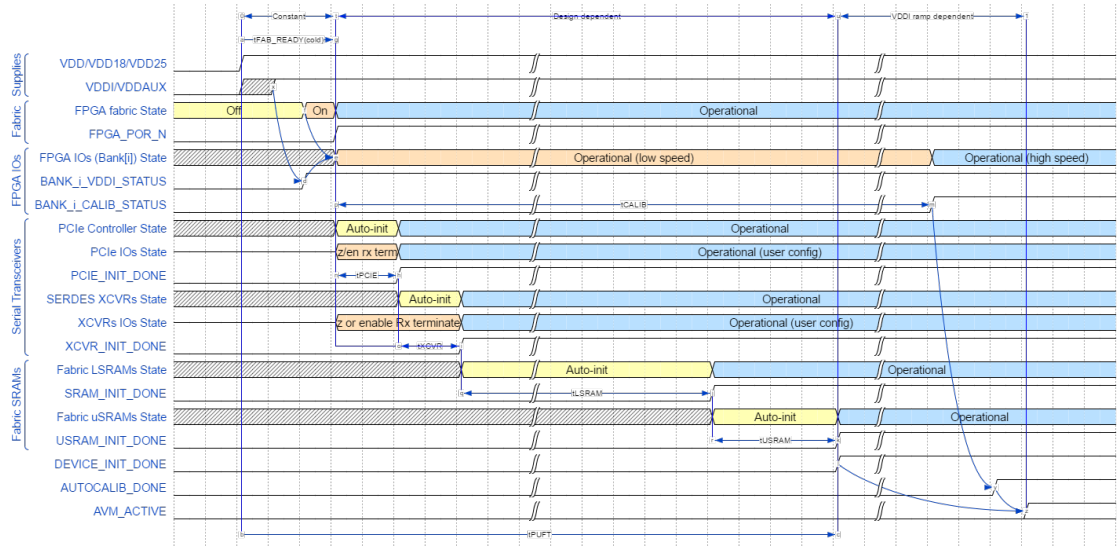
The following section describes characteristics of USPI switching.

Table 90 • SPI Macro Interface Timing Characteristics

Parameter	Symbol	V_{DDI} = 3.3 V Max	V_{DDI} = 2.5 V Max	V_{DDI} = 1.8 V Max	V_{DDI} = 1.5 V Max	V_{DDI} = 1.2 V Max	Unit
Propagation delay from the fabric to pins[1]	TPD_MOSI	0.8	1	1.2	1.4	1.6	ns
	TPD_MISO	3.5	3.75	4	4.25	4.5	ns
	TPD_SS	3.5	3.75	4	4.25	4.5	ns
	TPD_SCK	3.5	3.75	4	4.25	4.5	ns
	TPD_MOSI_OE	3.5	3.75	4	4.25	4.5	ns
	TPD_SS_OE	3.5	3.75	4	4.25	4.5	ns
	TPD_SCK_OE	3.5	3.75	4	4.25	4.5	ns

1. Assumes CL of the relevant I/O standard as described in the input and output delay measurement tables.

Figure 5 • Cold Reset Timing



Notes:

- The previous diagram showsthe case where VDDI/VDDAUX of I/O banks are powered either before or sufficiently soon after VDD/VDD18/VDD25 that the I/O bank enable time is measured from the assertion time of VDD/VDD18/VDD25 (that is, the PUFT specification). If VDDI/VDDAUX of I/O banks are powered sufficiently after VDD/VDD18/VDD25, then the I/O bank enable time is measured from the assertion of VDDI/VDDAUX and is not specified by the PUFT specification. In this case, I/O operation is indicated by the assertion of BANK_i_VDDI_STATUS, rather than being measured relative to FABRIC_POR_N negation.
- AUTOCALIB_DONE assertion indicates the completion of calibration for any I/O banks specified by the user for auto-calibration. AUTOCALIB_DONE asserts independently of DEVICE_INIT_DONE. It may assert before or after DEVICE_INIT_DONE and is determined by the following:
  - How long after VDD/VDD18/VDD25 that VDDI/VDDAUX are powered on. Note that if any of the user-specified I/O banks are not powered on within the auto-calibration timeout window, then AUTOCALIB_DONE doesn't assert until after this timeout.
  - The specified ramp times of VDDI of each I/O bank designated for auto-calibration.
  - How much auto-initialization is to be performed for the PCIe, SERDES transceivers, and fabric LSRAMs.
- If any of the I/O banks specified for auto-calibration do not have their VDDI/VDDAUX powered on within the auto-calibration timeout window, then it will be approximately auto-calibrated whenever VDDI/VDDAUX is subsequently powered on. To obtain an accurate calibration however, on such IO banks, it is necessary to initiate a re-calibration (using CALIB_START from fabric).
- AVM_ACTIVE only asserts if avionics mode is being used. It is asserted when the later of DEVICE_INIT_DONE or AUTOCALIB_DONE assert.

7.9.2 Warm Reset Initialization Sequence

The following warm reset timing diagram shows the initialization sequencing of the device when either DEVRST_N or TAMPER_RESET_DEVICE signals are asserted.

Table 101 • Cold and Warm Boot

Parameter	Symbol	Min	Typ	Max	Unit	Condition
The time from T_{FAB_READY} to ready to program through JTAG/SPI-Slave		0	0	0	ms	
The time from T_{FAB_READY} to auto-update start			T_{PUF_OVHD}[1]	T_{PUF_OVHD}[1]	ms	
The time from T_{FAB_READY} to programming recovery start			T_{PUF_OVHD}[1]	T_{PUF_OVHD}[1]	ms	
The time from T_{FAB_READY} to the tamper flags being available	T_{TAMPER_READY}	0	0	0	ms	
The time from T_{FAB_READY} to the Athena Crypto co-processor being available (for S devices only)	T_{CRYPTO_READY}	0	0	0	ms	

1. Programming depends on the PUF to power up. Refer to T_{PUF_OVHD} at section Secure NVM Performance (see page 58).

7.9.8 I/O Calibration

The following tables specify the initial I/O calibration time for the fastest and slowest supported VDDI ramp times of 0.2 ms to 50 ms, respectively. This only applies to I/O banks specified by the user to be auto-calibrated.

Table 102 • I/O Initial Calibration Time (TCALIB)

Ramp Time	Min (ms)	Max (ms)	Condition
0.2 ms	0.98	2.63	Applies to HSIO and GPIO banks
50 ms	41.62	62.19	Applies to HSIO and GPIO banks

Notes:

- The user may specify any VDDI ramp time in the range specified above. The nominal initial calibration time is given by the specified VDDI ramp time plus 2 ms.
- In order for IO calibration to start, VDDI and VDDAUX of the I/O bank must be higher than the trip point levels specified in I/O-Related Supplies (see page 66).

Table 103 • I/O Fast Recalibration Time (TRECALIB)

I/O Type	Min (ms)	Typ (ms)	Max (ms)	Condition
GPIO bank	0.16	0.20	0.24	GPIO configured for 3.3 V operation
HSIO bank	0.20	0.25	0.30	HSIO configured for 1.8 V operation

Note: In order to obtain fast re-calibration, the user must assert the relevant clock request signal from the FPGA fabric to the I/O bank controller.

The following table describes the time to enter Flash*Freeze Mode and to exit Flash*Freeze mode.

SigVer, DSA-2048/SHA-256	1024	9810527	10884
	8K	9597000	10719
Key Agreement (KAS), DH-3072 (p=3072, security=256)		4920705	9338
Key Agreement (KAS), DH-3072 (p=3072, security=256)[1]		78914533	9083

1. With DPA counter measures.

Table 122 • NRBG

Modes	Message Size (bits)	Athena TeraFire Crypto Core Clock-Cycles	CAL Delay In CPU Clock-Cycles
Instantiate: strength, s=256, 384-bit nonce, 384-bit personalization string		18221	2841
Reseed: no additional input, s=256		13585	1180
Reseed: 384-bit additional input, s=256		15922	1342
Generate: (no additional input), prediction resistance enabled, s= 256	128	15262	1755
	8K	27169	8223
Generate: (no additional input), prediction resistance disabled, s= 256	128	2138	1167
	8K	14045	8223
Generate: (384-bit additional input), prediction resistance enabled, s= 256	128	21299	1944
	8K	33206	8949
Generate: (384-bit additional input), prediction resistance disabled, s= 256	128	11657	1894
	8K	23564	8950
Un-instantiate		761	666

1. With DPA counter measures.